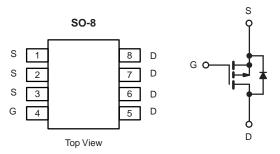
P-Channel 40 V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}$ (Ω)(Typ.)	I _D (A)	Q _g (Typ.)			
- 40	0.0094 at V _{GS} = - 10 V	- 18 ^d	35.4 nC			
- 40	0.0132 at V _{GS} = -4.5 V	- 15 ^d	33.4 110			



P-Channel MOSFET

FEATURES

• 100% R_g and UIS Tested

APPLICATIONS

- Adaptor Switch
- Load Switch
- **Power Management**
- Mobile Computing



R	0	Н	S
СО	MP	LIA	۱N

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	- 40	V	
Gate-Source Voltage		V _{GS}	± 20	V
	T _C = 25 °C		- 18 ^d	
Continuous Drain Current (T _{.I} = 150 °C)	T _C = 70 °C		- 15 ^d	
Continuous Brain Current (1) = 130 C)	T _A = 25 °C	l _D	- 14.7 ^{a, b}	
	T _A = 70 °C	1	- 11.7 ^{a, b}	Α .
Pulsed Drain Current (t = 300 μs)	I _{DM}	- 70	A	
Continuous Source-Drain Diode Current	T _C = 25 °C	l _a	- 18 ^d	
Continuous Source-Diain Diode Current	T _A = 25 °C	- I _S	- 3 ^{a, b}	
Avalanche Current	inche Current L = 0.1 mH		- 20	
Single-Pulse Avalanche Energy	L = 0.1 IIII	E _{AS}	20	mJ
	T _C = 25 °C		52	
Maximum Power Dissipation	T _C = 70 °C	P _D	33	w
Maximum Fower Dissipation	T _A = 25 °C] 'D	3.7 ^{a, b}	VV
	T _A = 70 °C		2.4 ^{a, b}	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C	
Soldering Recommendations (Peak Temperature) ^{e, f}		260		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{a, c}	t ≤ 10 s	R _{thJA}	26	33	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	1.9	2.4	C/VV	

Notes:

- a. Surface mounted on 1" x 1" FR4 board.
- b. t = 10 s.
- c. Maximum under steady state conditions is 81 °C/W.
- d. Package limited.

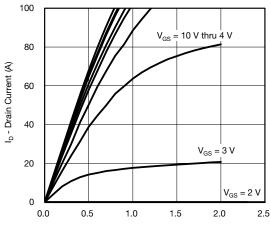


Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 40			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = - 250 μA		- 23		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			4.6		mv/·C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	- 1		- 2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = - 40 V, V _{GS} = 0 V			- 1	- 1 - 5 μΑ	
Zero Gate voltage Drain Current		V _{DS} = -40 V, V _{GS} = 0 V, T _J = 55 °C			- 5		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge -10 \text{ V}, V_{GS} = -10 \text{ V}$	- 30			Α	
Dunin Course On Chata Basistanasi	R	V _{GS} = - 10 V, I _D = - 10 A		0.0094	0.0125	Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 7 A		0.0132	0.0165	_ \(\(\)2	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 10 V, I _D = - 15 A		50		S	
Dynamic ^b							
Input Capacitance	C _{iss}			4280		pF	
Output Capacitance	C _{oss}	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		427			
Reverse Transfer Capacitance	C _{rss}			382			
Total Gate Charge	Qg	$V_{DS} = -15 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -10 \text{ A}$		73	110		
	□ Q _g			35.4	53	nC	
Gate-Source Charge	Q _{gs}	$V_{DS} = -15 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -10 \text{ A}$		10.6		- IIC	
Gate-Drain Charge	Q _{gd}			11.6			
Gate Resistance	R _g	f = 1 MHz	0.4	1.6	3.2	Ω	
Turn-On Delay Time	t _{d(on)}			11	22		
Rise Time	t _r	V_{DD} = - 15 V, R_L = 1.5 Ω		11	22		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong -10 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$		45	90		
Fall Time	t _f			8	16	nc	
Turn-On Delay Time	t _{d(on)}			55	100	ns	
Rise Time	t _r	$V_{DD} = -15 \text{ V}, R_{L} = 1.5 \Omega$		82	150		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong$ - 10 A, V_{GEN} = - 4.5 V, R_g = 1 Ω		40	80		
Fall Time	t _f			13	26		
Drain-Source Body Diode Characterist	ics						
Continous Source-Drain Diode Current	I _S	T _C = 25 °C			- 18	Α	
Pulse Diode Forward Current	I _{SM}				- 70	_ ^	
Body Diode Voltage	V_{SD}	I _S = - 3 A, V _{GS} = 0 V		- 0.74	- 1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			18	36	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	1 10 A dl/dt 100 A / 1- T 05 00		8	16	nC	
Reverse Recovery Fall Time		$I_F = -10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		7		ns	
Reverse Recovery Rise Time	t _b	7		11			

a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$ b. Guaranteed by design, not subject to production testing.

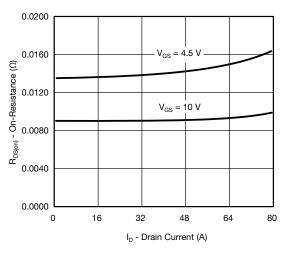


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

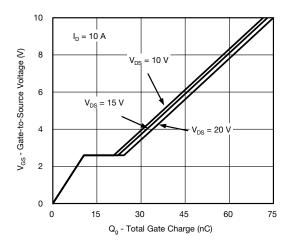


V_{DS} - Drain-to-Source Voltage (V)

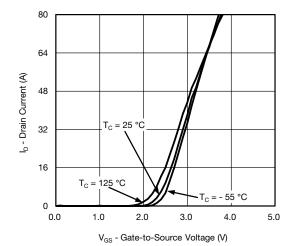
Output Characteristics



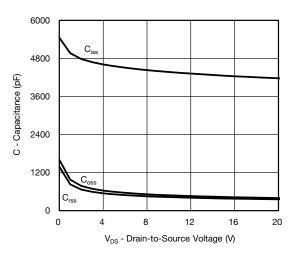
On-Resistance vs. Drain Current



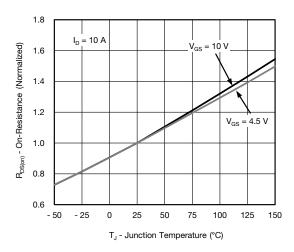
Gate Charge



Transfer Characteristics



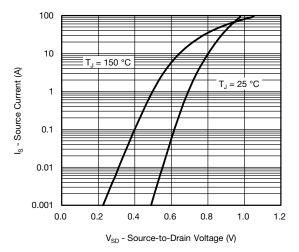
Capacitance



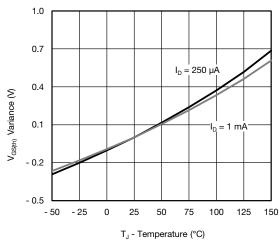
On-Resistance vs. Junction Temperature



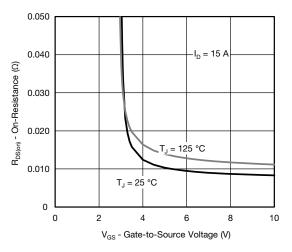
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



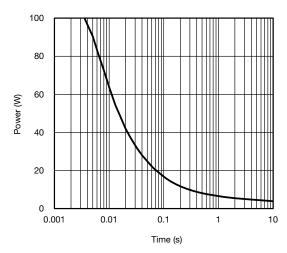
Source-Drain Diode Forward Voltage



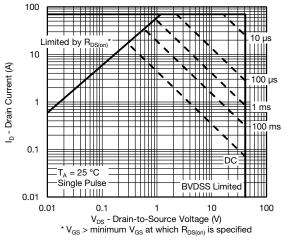
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage



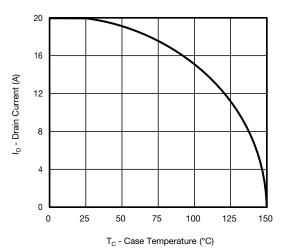
Single Pulse Power, Junction-to-Ambient



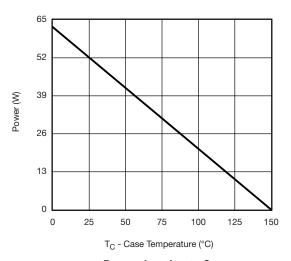
Safe Operating Area

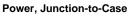


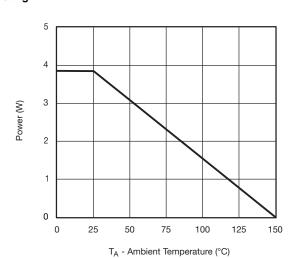
MOSFET TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



Current Derating*





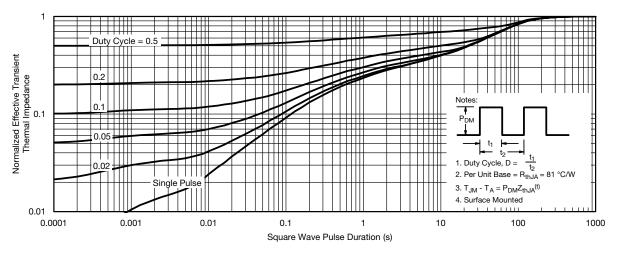


Power, Junction-to-Ambient

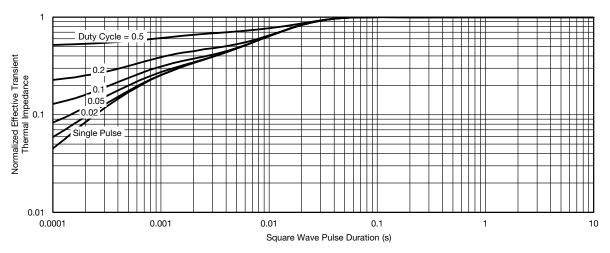
^{*} The power dissipation P_D is based on $T_{J(max.)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



Normalized Thermal Transient Impedance, Junction-to-Ambient

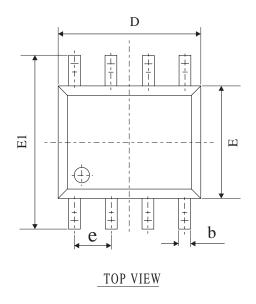


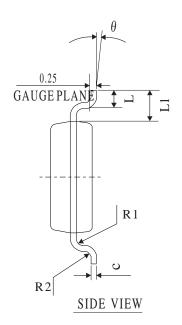
Normalized Thermal Transient Impedance, Junction-to-Case

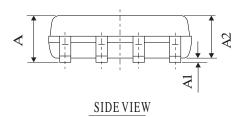




SOP-8 PACKAGE OUTLINE







COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	TYP	MAX	
A	1.30	1.60	1.85	
A1	0.03	0.15	0.28	
A2	1.20	1.45	1.70	
b	0.26	0.40	0.54	
С	0.132	0.203	0.273	
D	4.50	4.90	5.30	
Е	3.50	3.00	4.30	
E1	5.50	6.00	6.50	
L	0.30	0.70	1.10	
θ	2°	4°	6°	
L1	1.04REF			
e	1.27BSC			
R1	0.07TYP			
R2	0.07TYP			





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